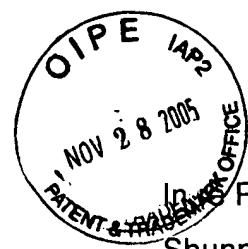


IN THE UNITED STATES PATENT AND TRADEMARK OFFICE



In the Patent Application of:

Shunpei YAMAZAKI et al.

Serial No. 09/832,867

Filed: April 12, 2001

For: LIGHT EMITTING DEVICE

COMPRISING THIN FILM

TRANSISTOR WITH DISTINCT

POSITION OF GATE ELECTRODE

AND IMPURITY REGIONS

) Group Art Unit: 2822

) Examiner: M. Lewis

) CERTIFICATE OF MAILING
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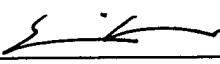
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This Information Disclosure Statement is being submitted with an RCE. Therefore, no fee is required.

Respectfully submitted,


Eric J. Robinson
Reg. No. 38,285

Robinson Intellectual Property Law Office, P.C.
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PTO/SB/08A (08-00)

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Sheet	1	of	2	Attorney Docket Number	0756-2294

U.S. PATENT DOCUMENTS

Examiner Initials*	Cite No. ¹	U.S. Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number	Kind Code ² (if known)			
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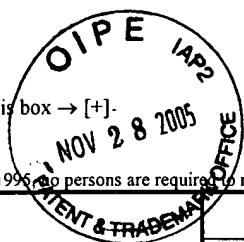
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		Office ³	Number ⁴	Kind Code ⁵ (if known)				
		JP	08-160464			06/21/1996		Abst.
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		R. SHIMOKAWA, et al., <i>Characterization of High-Efficiency Cast-Si Solar Cell Wafers by MBIC Measurement</i> , Japanese Journal of Applied Physics, May 1, 1988, Volume 27, No. 5, Pages 751-758.				
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				Application Number 09/832,867 Filing Date April 12, 2001 First Named Inventor Shunpei YAMAZAKI et al. Group Art Unit 2822 Examiner Name M. Lewis Attorney Docket Number 0756-2294
Sheet	2	of	2	

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Application Number	09/832,867
Filing Date	April 12, 2001
First Named Inventor	Shunpei YAMAZAKI, et al.
Group Art Unit	2822
Examiner Name	Monica Lewis
Attorney Docket Number	0756-2294

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Examiner Initials*	Cite No. ¹	Foreign Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ²
		Office ³	Kind Code ³ (if known) Number ⁴				
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